

# Image Quality and System Performance VII

Susan P. Farnand Frans Gaykema Editors

18–19 January 2010 San Jose, California, United States

Sponsored and Published by IS&T—The Society for Imaging Science and Technology SPIE

Volume 7529

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Please use the following format to cite material from this book:

Author(s), "Title of Paper," in Image Quality and System Performance VII, edited by Susan P. Farnand, Frans Gaykema, Proceedings of SPIE-IS&T Electronic Imaging, SPIE Vol. 7529, Article CID Number (2010).

ISSN 0277-786X ISBN 9780819479228

Copublished by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

and

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Printed in the United States of America.

Paper Numbering: Proceedings of SPIE follow an e-First publication model, with papers published first online and then in print and on CD-ROM. Papers are published as they are submitted and meet publication criteria. A unique, consistent, permanent citation identifier (CID) number is assigned to each article at the time of the first publication. Utilization of CIDs allows articles to be fully citable as soon they are published online, and connects the same identifier to all online, print, and electronic versions of the publication. SPIE uses a six-digit CID article numbering system in which:

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